

2SK2835

Chopper Regulator, DC-DC Converter and Motor Drive Applications

- Low drain-source ON resistance : $R_{DS(ON)} = 0.56 \Omega$ (typ.)
- High forward transfer admittance : $|Y_{fs}| = 4.5 \text{ S}$ (typ.)
- Low leakage current : $I_{DSS} = 100 \mu\text{A}$ (max) ($V_{DS} = 200 \text{ V}$)
- Enhancement-mode : $V_{th} = 1.5 \sim 3.5 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	200	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	200	V
Gate-source voltage	V_{GSS}	± 20	V
Drain current	DC (Note 1)	I_D	5
	Pulse (Note 1)	I_{DP}	20
Drain power dissipation	P_D	1.3	W
Single pulse avalanche energy (Note 2)	E_{AS}	65	mJ
Avalanche current	I_{AR}	5	A
Repetitive avalanche energy (Note 3)	E_{AR}	0.13	mJ
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	$-55 \sim 150$	$^\circ\text{C}$

Thermal Characteristics

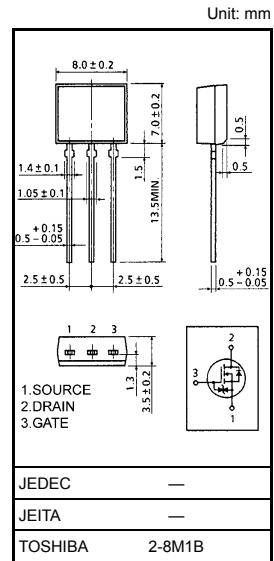
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	96.1	$^\circ\text{C} / \text{W}$

Note 1: Please use devices on condition that the channel temperature is below 150°C .

Note 2: $V_{DD} = 50 \text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 4.2 \text{ mH}$, $R_G = 25 \Omega$, $I_{AR} = 5 \text{ A}$

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.
Please handle with caution.



Weight: 0.54 g (typ.)

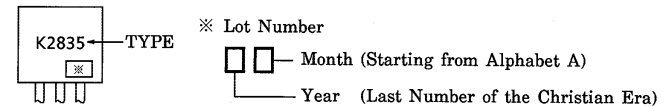
Electrical Characteristics ($T_a = 25^\circ\text{C}$)

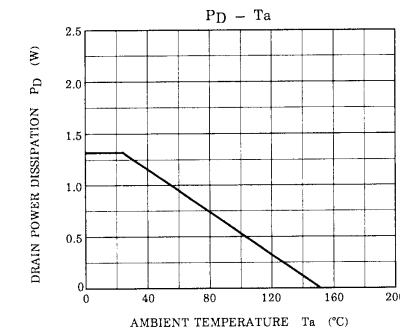
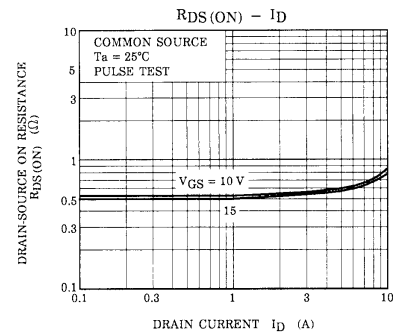
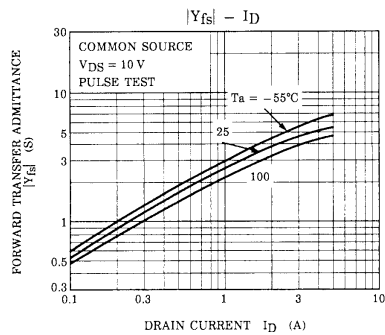
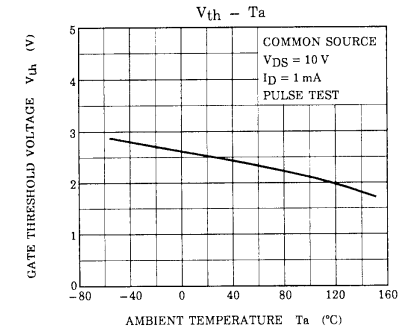
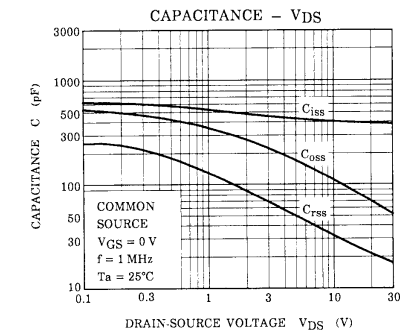
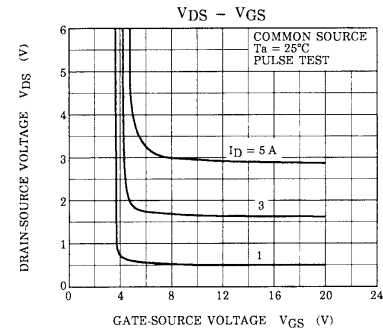
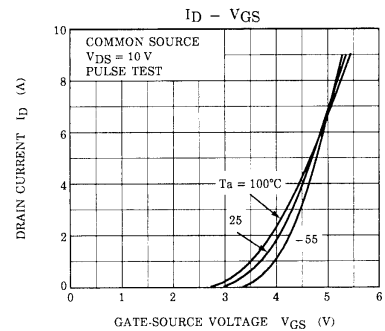
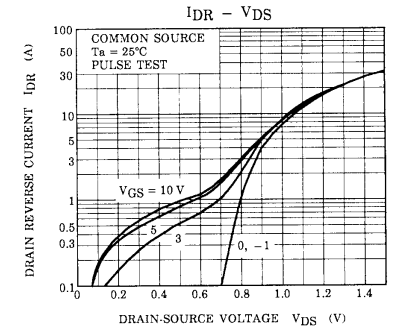
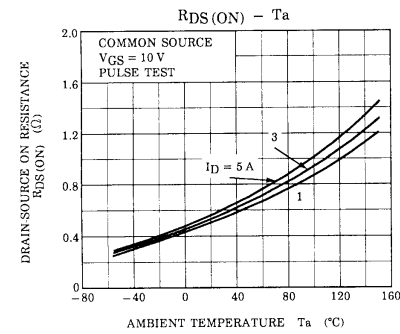
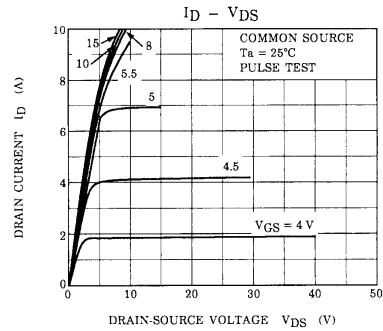
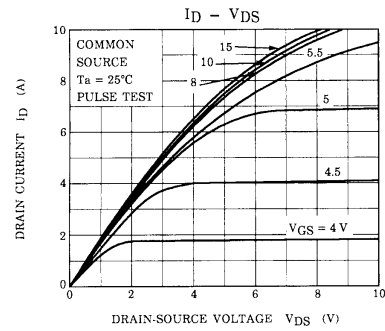
Characteristics		Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current		I_{GSS}	$V_{GS} = \pm 16 \text{ V}$, $V_{DS} = 0 \text{ V}$	—	—	± 10	μA
Drain cut-off current		I_{DSS}	$V_{DS} = 200 \text{ V}$, $V_{GS} = 0 \text{ V}$	—	—	100	μA
Drain-source breakdown voltage		$V_{(BR)DSS}$	$I_D = 10 \text{ mA}$, $V_{GS} = 0 \text{ V}$	200	—	—	V
Gate threshold voltage		V_{th}	$V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$	1.5	—	3.5	V
Drain-source ON resistance		$R_{DS(ON)}$	$V_{GS} = 10 \text{ V}$, $I_D = 2.5 \text{ A}$	—	0.56	0.8	Ω
Forward transfer admittance		$ Y_{fs} $	$V_{DS} = 10 \text{ V}$, $I_D = 2.5 \text{ A}$	2.0	4.5	—	S
Input capacitance		C_{iss}	$V_{DS} = 10 \text{ V}$, $V_{GS} = 0 \text{ V}$, $f = 1 \text{ MHz}$	—	440	—	pF
Reverse transfer capacitance		C_{rss}		—	35	—	
Output capacitance		C_{oss}		—	120	—	
Switching time	Rise time	t_r	<p>$I_D = 2.5 \text{ A}$ V_{OUT} $R_L = 40 \Omega$ $V_{DD} \approx 100 \text{ V}$ $\text{Duty} \leq 1\%$, $t_W = 10 \mu\text{s}$</p>	—	15	—	ns
	Turn-on time	t_{on}		—	20	—	
	Fall time	t_f		—	15	—	
	Turn-off time	t_{off}		—	60	—	
Total gate charge (gate-source plus gate-drain)		Q_g	$V_{DD} = 100 \text{ V}$, $V_{GS} = 10 \text{ V}$, $I_D = 5 \text{ A}$	—	10	—	nC
Gate-source charge		Q_{gs}		—	6	—	
Gate-drain ("miller") Charge		Q_{gd}		—	4	—	

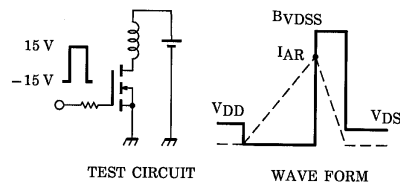
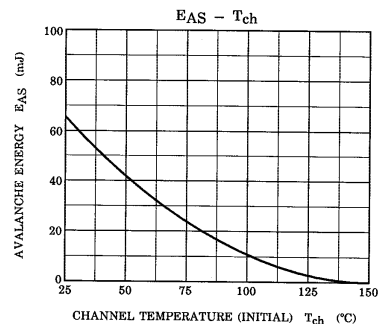
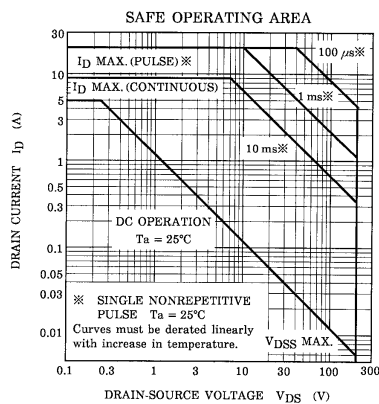
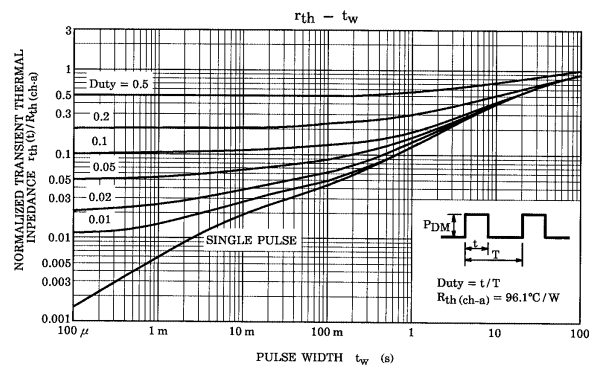
Source-Drain Ratings and Characteristics ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	—	—	—	5	A
Pulse drain reverse current (Note 1)	I_{DRP}	—	—	—	20	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = 5 \text{ A}$, $V_{GS} = 0 \text{ V}$	—	—	-2.0	V
Reverse recovery time	t_{rr}	$I_{DR} = 5 \text{ A}$, $V_{GS} = 0 \text{ V}$, $dI_{DR} / dt = 100 \text{ A} / \mu\text{s}$	—	150	—	ns
Reverse recovery charge	Q_{rr}		—	0.45	—	μC

Marking







$$R_G = 25 \Omega$$

$$V_{DD} = 25 \text{ V}, L = 4.2 \text{ mH}$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$

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